Requirement

Avg η_{mp}>38.5%;

Min η_{mp} > 36.2%

Characterization

Characterization

 $NP_{mp} > 0.98$

Qualification Tests Completed

Qty

100%

20

100% of

scribed

parts

Test Conditions

50 W/cm2 under ASTM

50. 75 & 100 W/cm²

ASTM 173G at 10°C

25°C, 65°C, and 110°C

LIV test before and after

Test

LIV

Temp

Weld

Intensity

Spectral

Degradation

Performance Tests

173G

weld

CPV Dense Array Solar Cells C3MJ Third Generation CPV Technology

Product Description

| Typical Aperture Area Efficiency | 38.5% |
|-----------------------------------|--------|
| Recommended operating temperature | <110°C |
| Epitaxial Structure | |

Triple junction solar cell on Germanium substrate GaInP (1.88 eV) / GaInAs (1.41 eV) / Ge (0.67 eV) *Metallization*

Silver metallization on front busbar and grid fingers Silver metallization with 500Å gold on back surface



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ENVIRONMENTAL MANAGEMENT SYSTEM CERTIFIED BY DNV Specifications Subject to Change without Notice.





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